



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AON6560**

**30V N-Channel AlphaMOS**

### General Description

- Latest Trench Power AlphaMOS (αMOS LV) technology
- Low  $R_{DS(ON)}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

### Product Summary

$V_{DS}$	30V
$I_D$ (at $V_{GS}=10V$ )	200A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 0.68mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 1.1mΩ

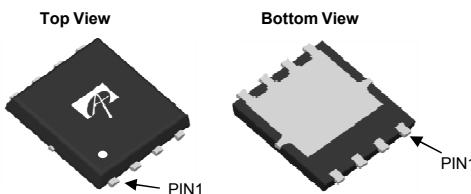
### Application

- High performance ORing, Efuse
- Ultra high current battery charge/discharge

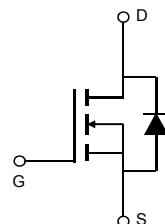
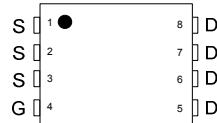
100% UIS Tested  
100%  $R_g$  Tested



DFN5X6



Top View



### Orderable Part Number

AON6560

### Package Type

DFN 5x6

### Form

Tape & Reel

### Minimum Order Quantity

3000

### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>G</sup>	$I_D$ <sup>T<sub>C</sub>=25°C</sup>	200	A
	$I_D$ <sup>T<sub>C</sub>=100°C</sup>	200	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	800	
Continuous Drain Current	$I_{DSM}$ <sup>T<sub>A</sub>=25°C</sup>	84	A
	$I_{DSM}$ <sup>T<sub>A</sub>=70°C</sup>	67	
Avalanche Current <sup>C</sup>	$I_{AS}$	80	A
Avalanche energy <sup>L=0.05mH C</sup>	$E_{AS}$	160	mJ
$V_{DS}$ Spike	10μs	$V_{SPIKE}$	V
Power Dissipation <sup>B</sup>	$P_D$ <sup>T<sub>C</sub>=25°C</sup>	208	W
	$P_D$ <sup>T<sub>C</sub>=100°C</sup>	83	
Power Dissipation <sup>A</sup>	$P_{DSM}$ <sup>T<sub>A</sub>=25°C</sup>	7.3	W
	$P_{DSM}$ <sup>T<sub>A</sub>=70°C</sup>	4.7	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	14	17	°C/W
		40	50	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	0.46	0.6	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{ID}=250\mu\text{A}, \text{V}_{\text{GS}}=0\text{V}$	30			V
$\text{I}_{\text{DSS}}$	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	$\mu\text{A}$
$\text{I}_{\text{GSS}}$	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm20\text{V}$			$\pm100$	nA
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.4	1.8	2.2	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$ $T_J=125^\circ\text{C}$		0.55	0.68	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=20\text{A}$		0.8	1	$\text{m}\Omega$
				0.85	1.1	$\text{m}\Omega$
$\text{g}_{\text{FS}}$	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=20\text{A}$		100		S
$\text{V}_{\text{SD}}$	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.65	1	V
$\text{I}_{\text{S}}$	Maximum Body-Diode Continuous Current <sup>G</sup>				200	A
<b>DYNAMIC PARAMETERS</b>						
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$		11500		pF
$\text{C}_{\text{oss}}$	Output Capacitance			3400		pF
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance			3100		pF
$\text{R}_{\text{g}}$	Gate resistance	$\text{f}=1\text{MHz}$		1.2		$\Omega$
<b>SWITCHING PARAMETERS</b>						
$\text{Q}_{\text{g}}(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		230	325	nC
$\text{Q}_{\text{g}}(4.5\text{V})$	Total Gate Charge			130	185	nC
$\text{Q}_{\text{gs}}$	Gate Source Charge			28		nC
$\text{Q}_{\text{gd}}$	Gate Drain Charge			92		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{R}_{\text{L}}=0.75\Omega, \text{R}_{\text{GEN}}=3\Omega$		16		ns
$t_{\text{r}}$	Turn-On Rise Time			42		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			115.5		ns
$t_{\text{f}}$	Turn-Off Fall Time			91.5		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		38.5		ns
$\text{Q}_{\text{rr}}$	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=20\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$		120		nC

A. The value of  $R_{\text{DS(on)}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\text{DS(on)}} \leq 10\text{s}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

D. The  $R_{\text{DS(on)}}$  is the sum of the thermal impedance from junction to case  $R_{\text{JJC}}$  and case to ambient.

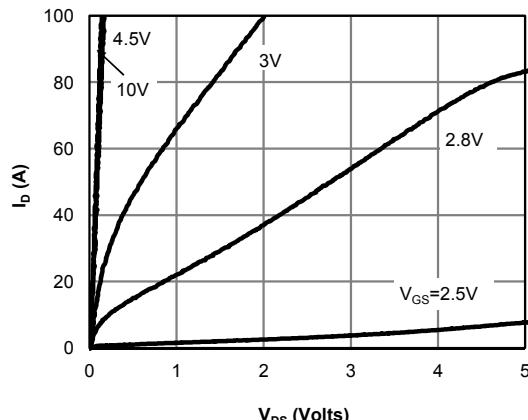
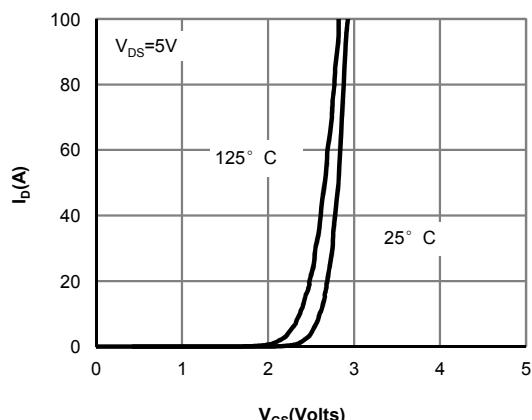
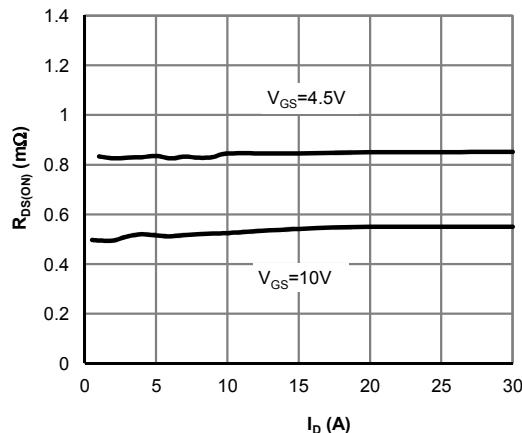
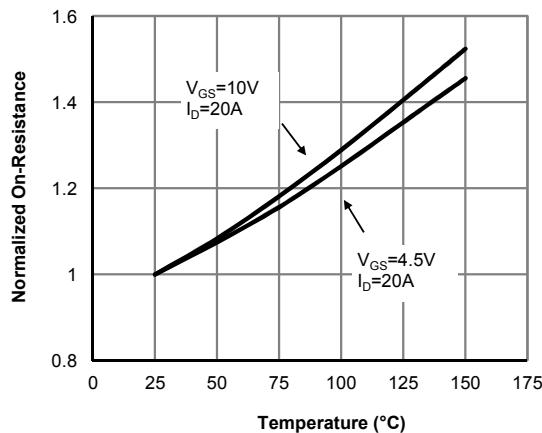
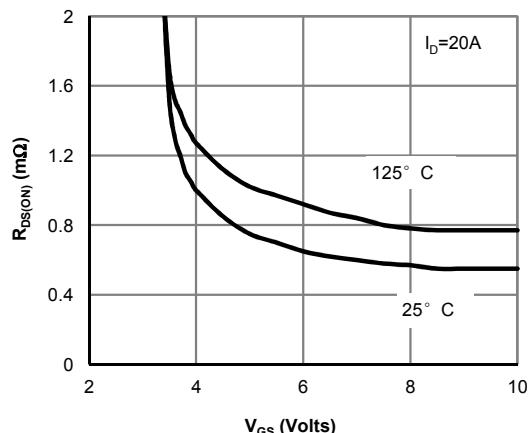
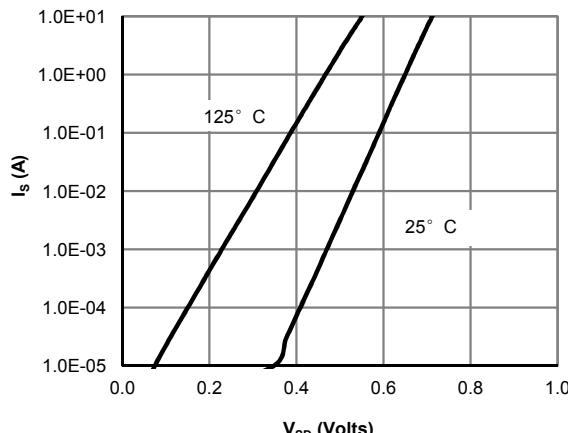
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

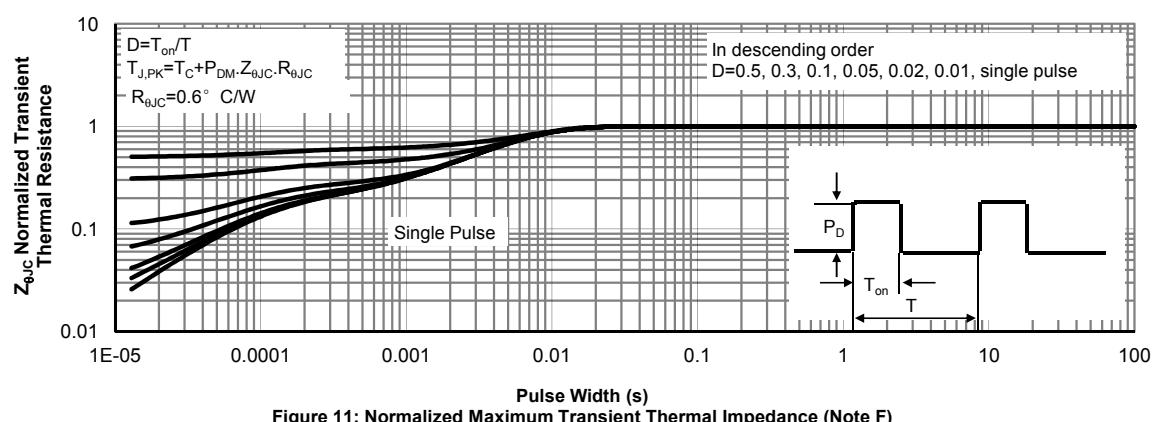
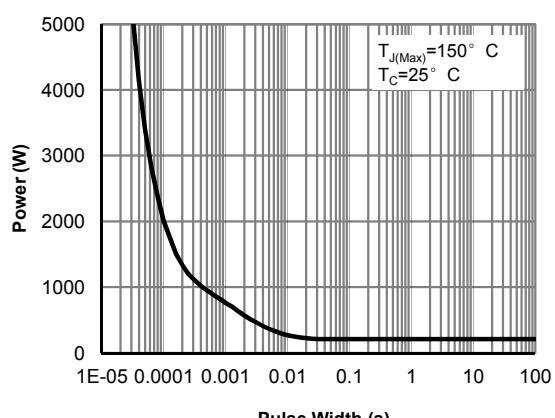
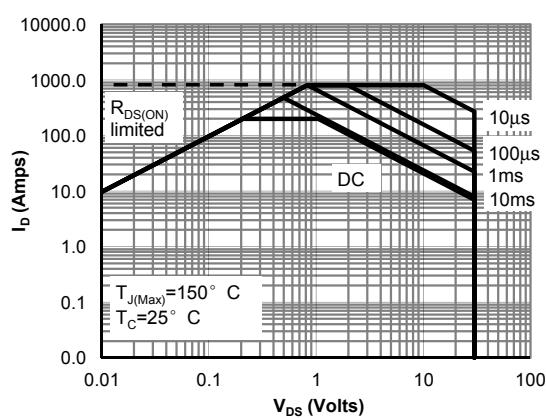
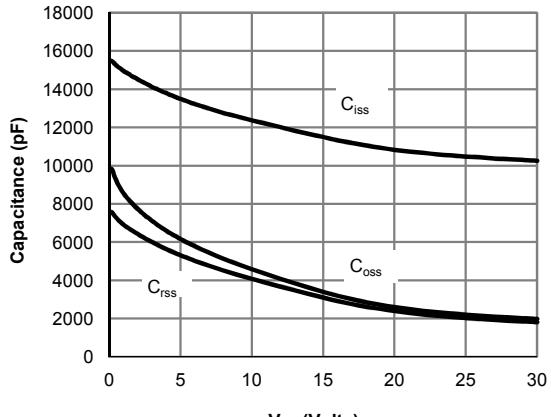
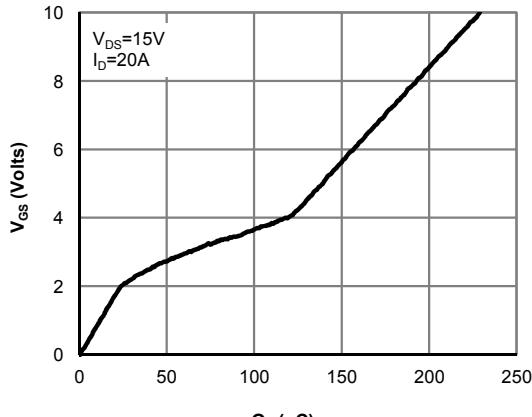
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


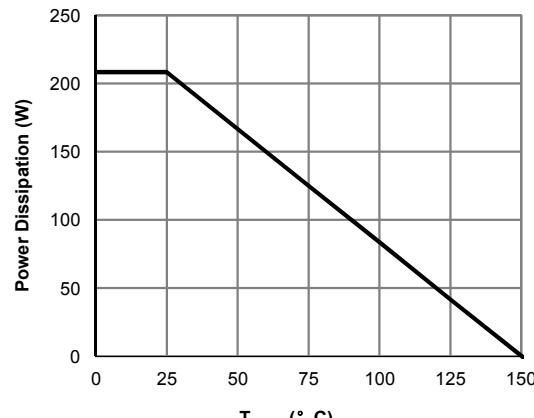
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 12: Power De-rating (Note F)

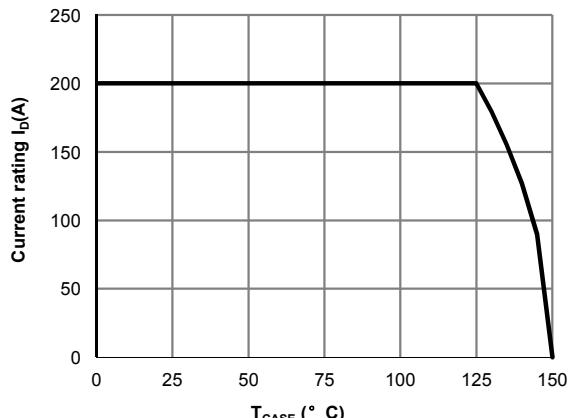


Figure 13: Current De-rating (Note F)

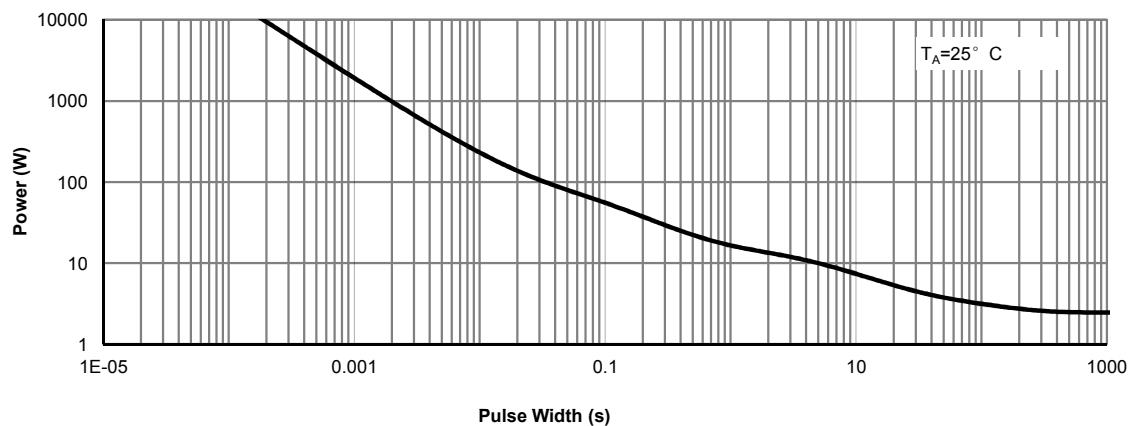


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

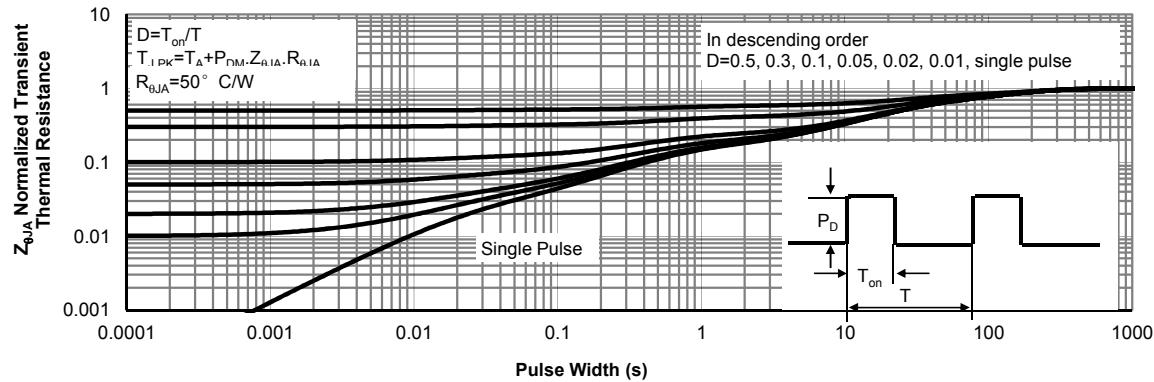
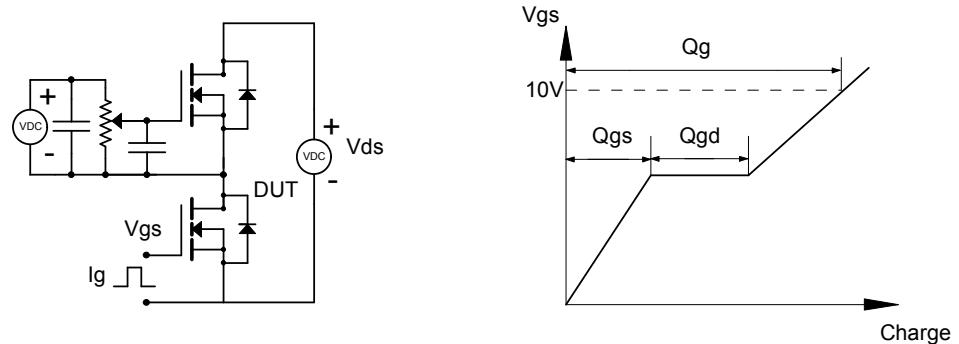
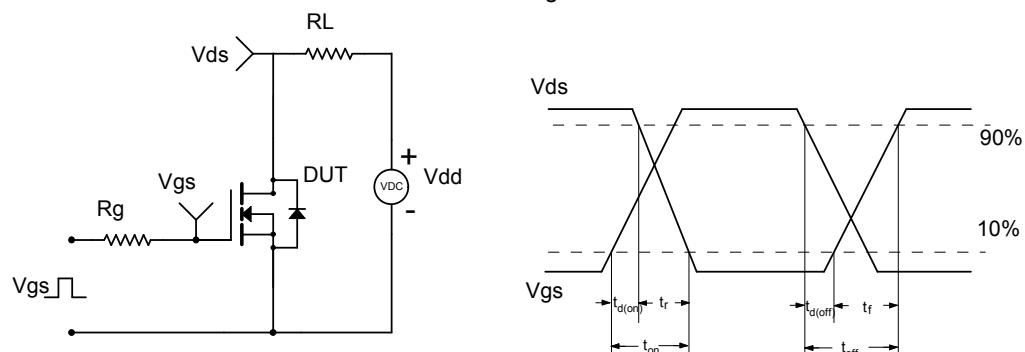
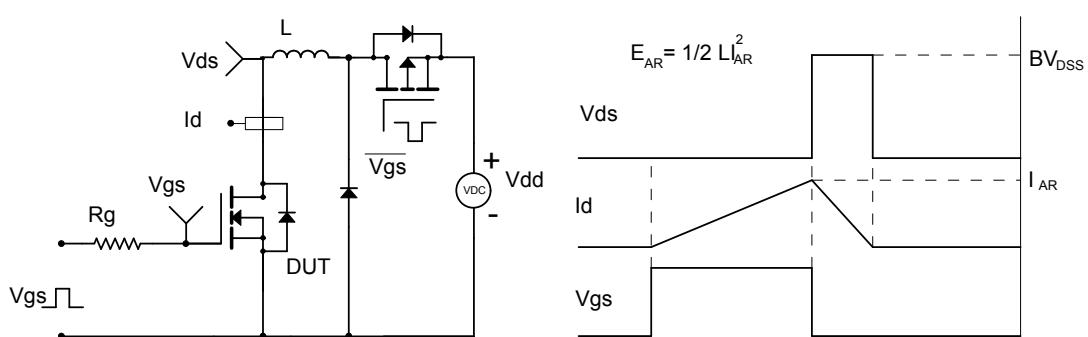


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
